Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/646,332	GEEN, JOHN A.
Examiner	Art Unit
Helen C. Kwok	2856

	SEARCHED				
Class	Subclass	Date	Examiner		
73	504.02	5/19/2005	нк		
73	504.04	5/19/2005	нк		
73	504.12	5/19/2005	нк		
73	504.14	5/19/2005	нк		
73	504.15	5/19/2005	нк		
73	514.32	5/19/2005	нк		
73	514.16	5/19/2005	нк		
73	514.29	5/19/2005	нк		
73	514.36	5/19/2005	нк		
73	514.37	5/19/2005	нк		
73	514.38	5/19/2005	нк		
73	514.23	5/19/2005	нк		
73	514.24	5/19/2005	нк		

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